

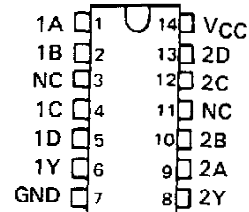
DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

SN5422, SN54LS22, SN54S22,
SN7422, SN74LS22, SN74S22

DECEMBER 1983 — REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chlp Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

SN5422, SN54LS22, SN54S22 . . . J OR W PACKAGE
SN7422 . . . N PACKAGE
SN74LS22, SN74S22 . . . D OR N PACKAGE
(TOP VIEW)

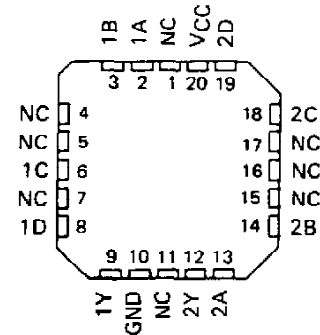


description

These devices contain two independent 4-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher V_{OH} levels.

The SN5422, SN54LS22 and SN54S22 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7422, SN74LS22, and SN74S22 are characterized for operation from 0°C to 70°C.

SN54LS22, SN54S22 . . . FK PACKAGE
(TOP VIEW)

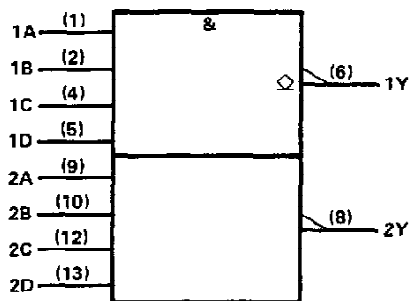


NC—No internal connection

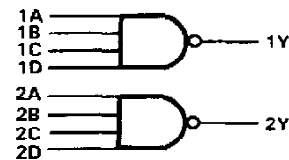
FUNCTION TABLE (each gate)

INPUTS				OUTPUT
A	B	C	D	Y
H	H	H	H	L
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H

logic symbol†



logic diagram



positive logic

$$Y = \overline{A \cdot B \cdot C \cdot D} \text{ or } Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$$

† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

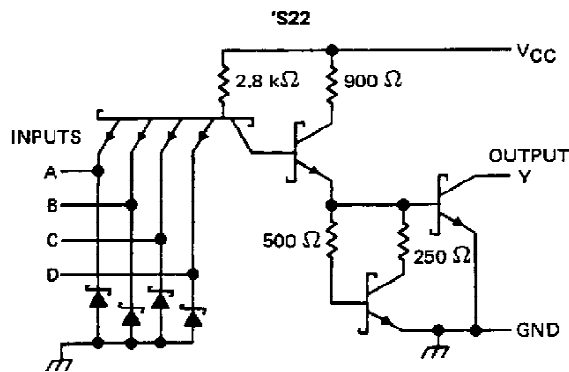
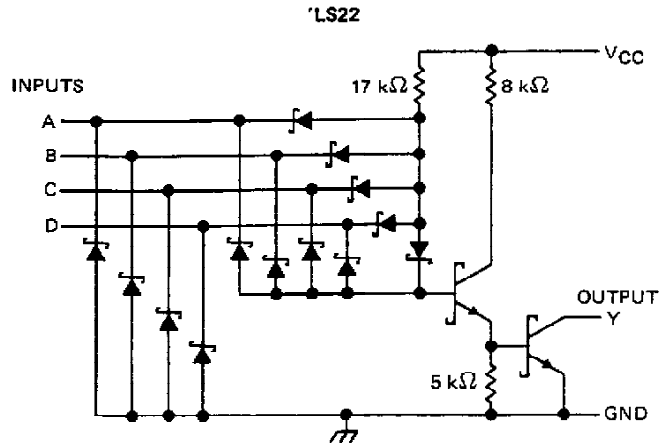
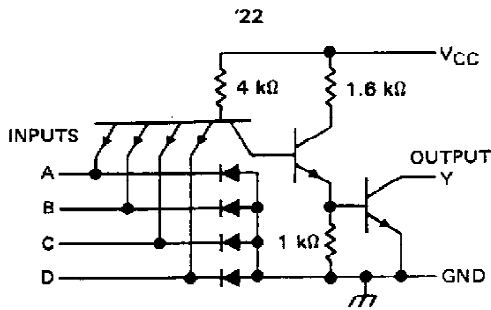
Pin numbers shown are for D, J, N, and W packages.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



**SN5422, SN54LS22, SN54S22,
SN7422, SN74LS22, SN74S22**
DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (See Note 1)	7 V
Input voltage: '22, 'S22	5.5 V
'LS22	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



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SN5422, SN7422

DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	SN5422			SN7422			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
V _{OH} High-level output voltage			5.5			5.5	V
I _{OL} Low-level output current			16			16	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5422			SN7422			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -12 mA			-1.5			-1.5	V
I _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 5.5 V						0.25	mA
	V _{CC} = MIN, V _{IL} = 0.7 V, V _{OH} = 5.5 V			0.25				
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.4 V			40			40	μA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-1.6			-1.6	mA
I _{CCH}	V _{CC} = MAX, V _I = 0		2	4		2	4	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		6	11		6	11	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 4 k Ω,	C _L = 15 pF		35	45	ns
t _{PHL}			R _L = 400 Ω,	C _L = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.


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SN54LS22, SN74LS22

DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	SN54LS22			SN74LS22			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage			0.7			0.8	V
V_{OH} High-level output voltage			5.5			5.5	V
I_{OL} Low-level output current			4			8	mA
T_A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54LS22			SN74LS22			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V_{IK}	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.5			-1.5	V
I_{OH}	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{OH} = 5.5 \text{ V}$			0.1			0.1	mA
V_{OL}	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V
	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 8 \text{ mA}$					0.35	0.5	
I_I	$V_{CC} = \text{MAX}, V_I = 7 \text{ V}$			0.1			0.1	mA
I_{IH}	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$			20			20	μA
I_{IL}	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$			-0.4			-0.4	mA
I_{CCH}	$V_{CC} = \text{MAX}, V_I = 0$		0.4	0.8		0.4	0.8	mA
I_{CCL}	$V_{CC} = \text{MAX}, V_I = 4.5 \text{ V}$		1.2	2.2		1.2	2.2	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	Any	Y	$R_L = 2 \text{ k}\Omega, C_L = 15 \text{ pF}$		17	32	ns
t_{PHL}					15	26	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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SN54S22, SN74S22

DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	SN54S22			SN74S22			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage				0.8			V
V _{OH} High-level output voltage				5.5			V
I _{OL} Low-level output current				20			mA
T _A Operating free-air temperature	-55			125			°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54S22			SN74S22			UNIT	
		MIN	TYP‡	MAX	MIN	TYP‡	MAX		
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.2			-1.2	V	
I _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 5.5 V						0.25	mA	
	V _{CC} = MIN, V _{IL} = 0.7 V, V _{OH} = 5.5 V			0.25					
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 20 mA			0.5			0.5	V	
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA	
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			50			50	μA	
I _{IL}	V _{CC} = MAX, V _I = 0.5 V			-2			-2	mA	
I _{CCH}	V _{CC} = MAX, V _I = 0			3	6.6		3	6.6	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V			10	18		10	18	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 280 Ω,	C _L = 15 pF	2	5	7.5	ns
t _{PHL}					2	4.5	7	
t _{PLH}			R _L = 280 Ω,	C _L = 50 pF	7.5			ns
t _{PHL}					7			

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.


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